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Docket No.: M4065.0904/P904

(PATENT)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: Chandra Mouli

Application No.: 10/602,716

Confirmation No.: 9955

Filed: June 25, 2003

Art Unit: 2811

For:

TAILORING GATE WORK-FUNCTION

IN IMAGE SENSORS

Examiner: D. Kang

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT (IDS)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with 37 CFR 1.97, Applicant hereby makes of record the following additional documents. A PTO Form SB/08 and a full copy of each of the documents required under 37 CFR 1.98(a)(2) accompany this statement.

Applicant has become aware of the following documents, cited in an International Search Report issued November 30, 2004, in international application no. PCT/US2004/020010, which corresponds to the above referenced application, and in accordance with 37 CFR 1.97(c) and (e)(1) or (b)(3), hereby submits these documents for the Examiner's consideration. These documents are cited on the enclosed PTO Form SB/08, and a copy of the International Search Report and of each document required under 37 CFR 1.98(a)(2) cited thereon are enclosed as well.

This statement is not to be interpreted as a representation that the cited documents are material, that an exhaustive search has been conducted, or that no other relevant information exists. Nor shall the citation of any document herein be construed *per* 

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se as a representation that such document is prior art. Moreover, Applicant understands the Examiner will make an independent evaluation of the cited documents.

The undersigned hereby certifies that each item contained in this Supplemental Information Disclosure Statement was cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Supplemental Information Disclosure Statement. Furthermore, in accordance with 37 CFR 1.704(d), Applicant notes that to our knowledge this communication was not received by any individual designated in 1.56(c) more than thirty days prior to the filing of this statement.

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-1073, under Order No. M4065.0904/P904.

Dated: December 14, 2004

Respectfully submitted,

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PTO/SB/08a/b (08-03)

Approved for use through 07/31/2006. OMB 0651-0031

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Under the Paperwo

Substitute for form 1449A/B/PTO				Complete if Known		
"				Application Number	10/602,716-Conf. #9955	
11	NFORMATION	N DIS	CLOSURE	Filing Date	June 25, 2003	
STATEMENT BY APPLICANT			PPLICANT	First Named Inventor	Chandra Mouli	
	(Use as many sheets as necessary)			Art Unit	2811	
				Examiner Name	D. Kang	
Sheet	1	of	1	Attorney Docket Number	M4065.0904/P904	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Document Number  Number-Kind Code <sup>2</sup> ( if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	2002/0190287	12/19/2002	Mann et al.	_

		FOREI	GN PATENT D	OCUMENTS		
Examiner	Cite	Foreign Patent Document	Publication	Name of Patentee or	Pages, Columns, Lines,	
Initials*	No.1	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	Date MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear	T⁵
	ВА	EP 0 798 785	10/01/1997			
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at <a href="https://www.uspto.gov">www.uspto.gov</a> or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>8</sup> Applicant is to place a check mark here if English language Translation is attached.

	NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²			
	CA	Kim, K.T. et al. – "Tungsten Silicide/Titanium Nitride Compound Gate," June 4, 1990, Symposium on VLSI Technology, Honolulu, June 4-7, 1990, New York, IEEE, US, pgs 115-116.				
	СВ	Long, Wei et al. – "Dual-Material Gate (DMG) Field Effect Transistor," May 1999, IEEE Transactions on Electron Devices, IEEE Inc. New York, US, pgs. 865-870.				
	СС	Ponomarev, Y.V. et al. – "Gate-Workfunction Engineering Using Poly-(Si,Ge) for High-Performance 0.18 µm CMOS Technology," International Electron Devices Meeting 1997, IEDM Technical Digest, Washington, DC, Dec. 7-10, 1997, New York, NY, IEEE, US, 12/7/1997, pgs. 829-832.				
	CD	Yagishita, Atsushi et al. – "Dynamic Threshold Voltage Damascene Metal Gate MOSFET (DT-DMG-MOS) Technology for Very Low Voltage Operation of Under 0.7 V," IEEE Transactions on Electron Devices, IEEE Inc. New York, US, vol. 49, no. 3, March 2002, pges. 422-428.				
	CE	International Search Report dated 11/30/2004.				

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Examiner	Date
Signature	Considered

<sup>&</sup>lt;sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.